

**Search Notes**

Application/Control No.

10/734,226

Examiner

Eric B. Chen

Applicant(s)/Patent under  
Reexamination

LEE ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Performed inventor search for double patenting (PALM, eDAN)	7/13/2005	EC
EAST (all databases - see search history printout)	7/14/2005	EC
438/3,706,710,719,720,911 (text search only - see search history printout) (consulted L. Vinh - AU 1765)	7/14/2005	EC